A multi-stimuli-responsive $CsPbBr_3$@PL-MOFs functional anti-counterfeiting material

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Supporting Figures.

Fig. S1 (a) The XRD patterns of **simulated HPU-22** and **synthesized HPU-22**; (b) the SEM image and (c) elemental mapping of **HPU-22**.

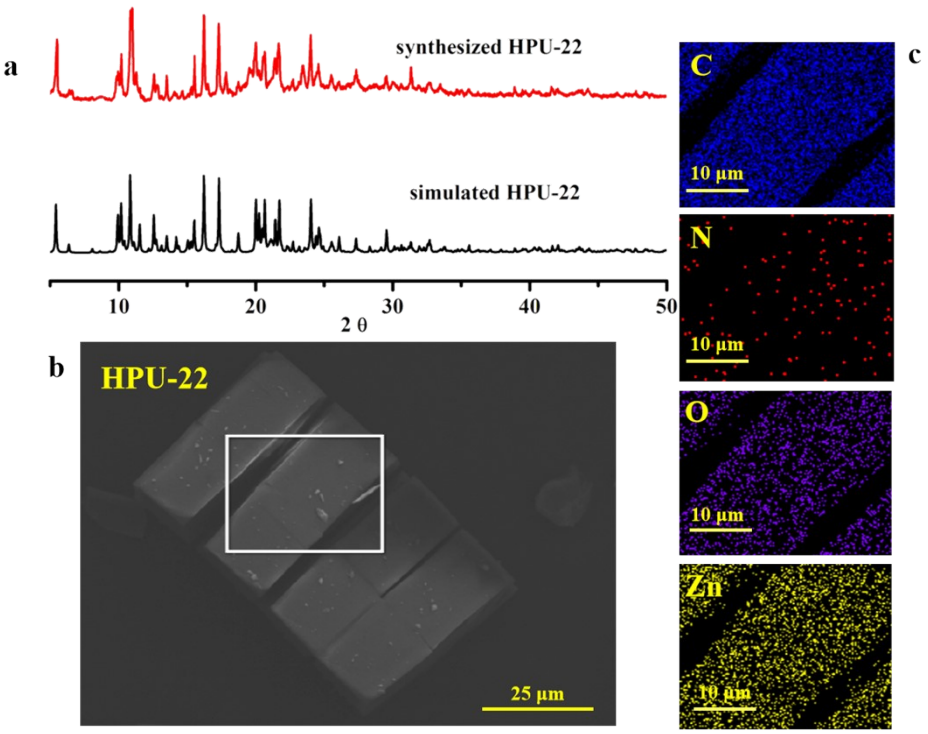
Fig. S2 XPS survey spectra of **$CsPbBr_3$@BT@HPU-22**.

Fig. S3 The PXRD patterns of **$CsPbBr_3$@HPU-22** after moisture treating for different times.

Fig. S4 The XPS results of **HPU-22**, **$CsPbBr_3$@HPU-22** and **H_2O@$CsPbBr_3$@HPU-22** after drying.

Fig. S5 The PL properties data of **HPU-22** treated by HCl and Et_3N.

Fig. S6 The PXRD patterns of **HPU-22**, **HPU-22** treated by HCl and **HPU-22** treated by HCl and Et_3N.



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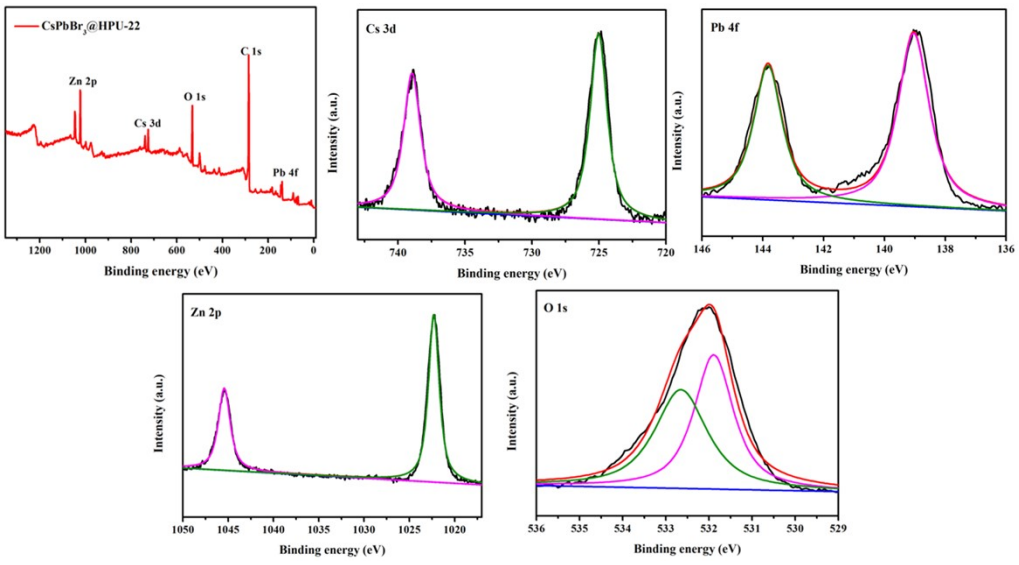

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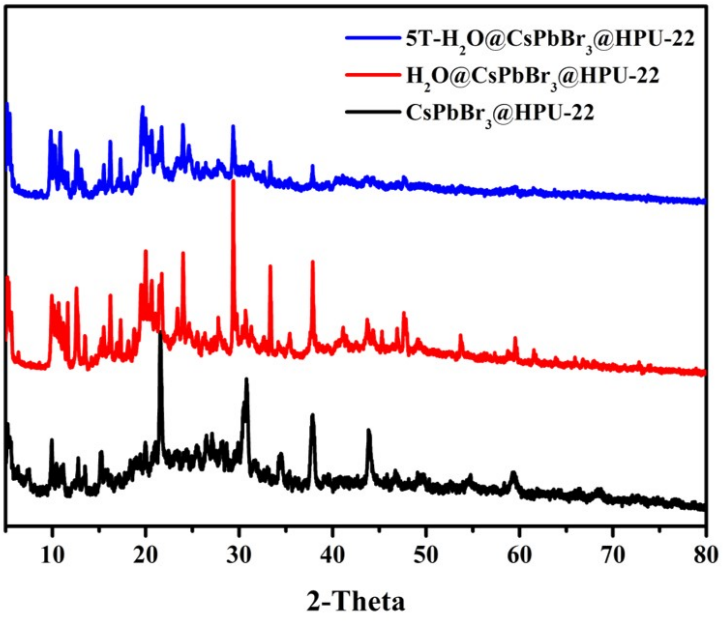

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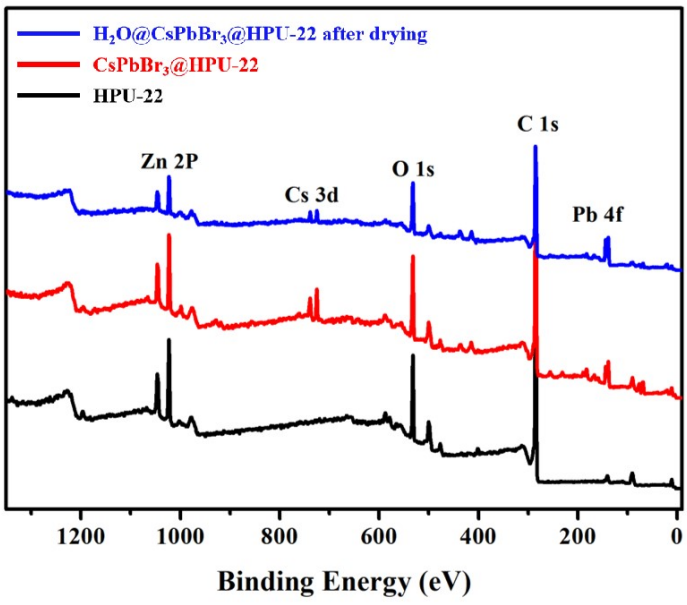

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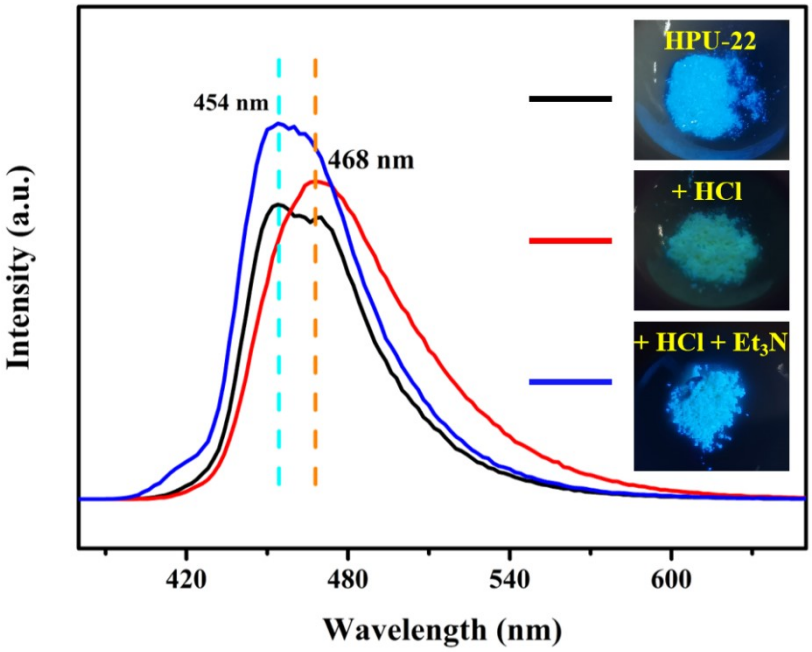

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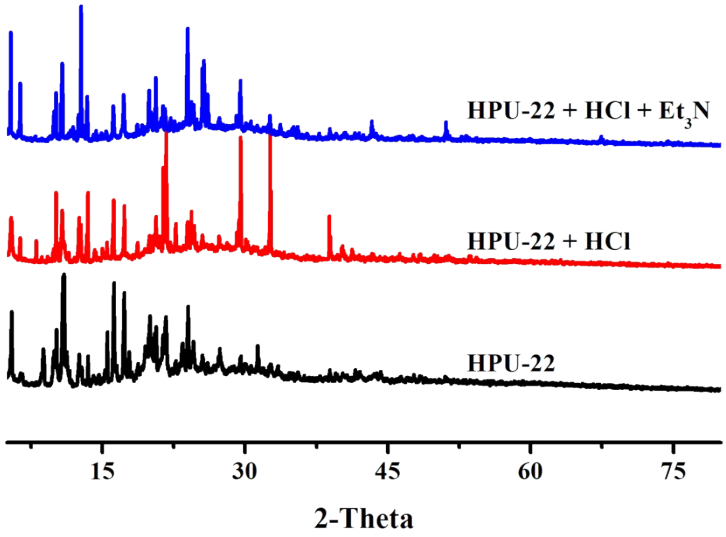

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